

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

<b>INFORMATION DISCLOSURE STATEMENT</b>		Docket Number <b>10191/1614</b>	
Application Number To Be Assigned	Filing Date Herewith	Examiner To Be Assigned	Art Unit To Be Assigned
Title <b>METHOD FOR ELIMINATING DEFECTS IN SILICON ELEMENTS THROUGH SELECTIVE ETCHING</b>		Applicant(s) <b>Richard SPITZ et al.</b>	

Address to:  
Assistant Commissioner  
for Patents  
Washington, D.C. 20231

1. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicant(s) hereby bring the following reference(s) to the attention of the Examiner. The reference(s) are listed on the attached modified PTO Form No. 1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
2. A copy of each patent, publication or other information listed on the modified PTO form 1449 is enclosed, except as otherwise indicated on the modified PTO form 1449.

Dated: 12/25/79

By: Richard L. Mayer  
Richard L. Mayer (Reg. No. 22,490)

KENYON & KENYON  
One Broadway  
New York, N.Y. 10004  
(212) 425-7200 (telephone)  
(212) 425-5288 (facsimile)

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT  
PTO FORM 1449**

ATTY. DOCKET NO.  
**10191/1614**

SERIAL NO.

Not yet assigned  
**08/728720**

APPLICANT(s)

**Richard SPITZ et al.**

FILING DATE  
Herewith

GROUP  
Not yet assigned

**U. S. PATENT DOCUMENTS**

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
	5,693,182*	December 2, 1997	Mathuni			
	5,350,480*	September 27, 1994	Gray			

\*Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
						YES	NO
	DE 35 06 995 *	28 August 1986	Fed. Rep. of Germany			X*	
	EP 0 878 824 *	24 April 1998	Europe			X*	
	JP 03 012921 ✓	21 January 1991	Japan			X*	
	JP 08 031785 *	2 February 1996	Japan			X*	

\*Copy of reference is not enclosed because reference is cited and described in Search Report (copy of reference provided by International Searching Authority).

**OTHER DOCUMENTS**

EXAMINER INITIAL		AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
		Patent Abstract of Japan, Vol. 015, No. 125 (1-1050) (27-3-91)*
		Patent Abstract of Japan, Vol. 1996, No. 06 (28/6/96)*

\*Copy of reference is not enclosed because reference is cited and described in Search Report (copy of reference provided by International Searching Authority).

EXAMINER

DATE CONSIDERED